

<b>Notice of References Cited</b>	Application/Control No. 10/047,686	Applicant(s)/Patent Under Reexamination KOSHIDA ET AL	
	Examiner Tae H Yoon	Art Unit 1714	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0002225 A1	01-2002	Reil, Frank	524/358
	B	US-			
	C	US-			
	D	US-			
	E	US-			
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**FOREIGN PATENT DOCUMENTS**

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